Thin Film X-Ray Diffraction Tutorial

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TOPICS COVERED:

Refresher on basics of x-ray diffraction (XRD).

XRD for epitaxial thin films: θ-2θ scans, ϕ-scans.

OUTCOMES:

Determine strain state of an epitaxial thin film.

Determine phase purity, epitaxial relationship of a thin film.

Identify film/substrate heterostructures from a set of XRD data.

DATE: Thursday 5th July 2018
TIME: 2:00PM–4:00PM

VENUE: UNSW, Chemical Sciences Building, M10

RSVP: UNSWnode@fleet.org.au

FLEET
ARC CENTRE OF EXCELLENCE IN FUTURE LOW-ENERGY ELECTRONICS TECHNOLOGIES